# **BUK664R4-55C**



# N-channel TrenchMOS intermediate level FET Rev. 03 — 21 December 2010

Product data sheet

## **Product profile**

#### 1.1 General description

Intermediate level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

#### 1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

#### 1.3 Applications

- 12 V and 24 V automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$		-	-	55	V
I <sub>D</sub>	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u>	[1]	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	204	W
Static cha	aracteristics						
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 13</u>		-	11.1	13	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 14		-	4.2	4.9	mΩ



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D = 100 \text{ A}; V_{sup} \le 55 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 \text{ °C}$	-	-	263	mJ
Dynamic characteristics						
$Q_{GD}$	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 18</u> ; see <u>Figure 17</u>	-	31.5	-	nC

<sup>[1]</sup> Continuous current is limited by package.

# 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

#### SOT404 (D2PAK)

# 3. Ordering information

Table 3. Ordering information

Type number	e number Package		
	Name	Description	Version
BUK664R4-55C	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	55	V
$V_{GS}$	gate-source voltage	DC	<u>[1]</u>	-16	16	V
		pulsed	[2]	-20	20	V
I <sub>D</sub>	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{}$	[3]	-	100	Α
		$T_{mb} = 100  ^{\circ}\text{C};  V_{GS} = 10  \text{V};  \text{see}  \frac{\text{Figure 1}}{}$		-	97	Α
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; see Figure 3		-	550	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	204	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	diode					
Is	source current	T <sub>mb</sub> = 25 °C	[3]	-	100	Α
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	550	Α
Avalanche rug	ggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 100 A; $V_{sup} \le 55$ V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C		-	263	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy		[4][5][6]	-	-	J

<sup>[1] -16</sup> V accumulated duration not to exceed 168 hrs.

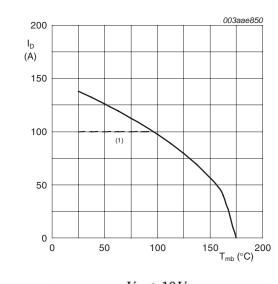
<sup>[2]</sup> Accumulated pulse duration not to exceed 5 mins.

<sup>[3]</sup> Continuous current is limited by package.

<sup>[4]</sup> Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

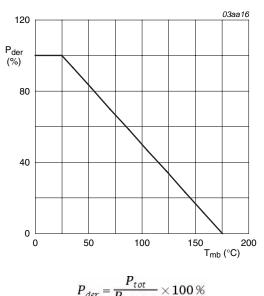
<sup>[5]</sup> Repetitive avalanche rating limited by an average junction temperature of 170 °C.

<sup>[6]</sup> Refer to application note AN10273 for further information.



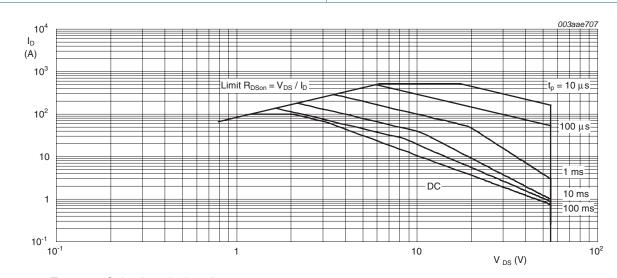
 $V_{GS} \ge 10 \, V$ (1) Capped at 100 A due to package.

Continuous drain current as a function of Fig 1. mounting base temperature



 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$ 

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$  °C;  $I_{DM}$  is a single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

## **Thermal characteristics**

Table 5. **Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.74	K/W

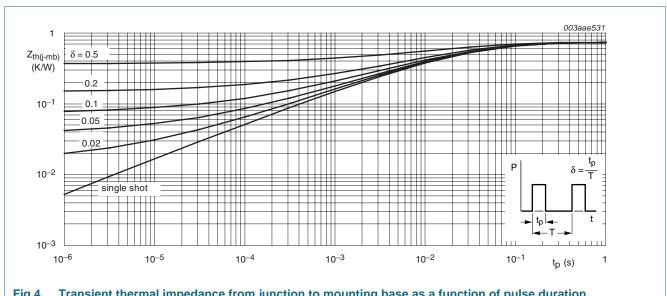


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	racteristics		144111	יאףי	max	Cint
V <sub>(BR)DSS</sub>		$I_D = 250 \mu A; V_{GS} = 0 V; T_i = 25 °C$	55	-	-	V
(511)500	g-	$I_D = 250 \mu\text{A};  V_{GS} = 0  V;  T_i = -55 ^{\circ}\text{C}$	27	-	-	V
		$I_D = 250 \mu\text{A};  V_{GS} = 0  V;  T_i = -55 ^{\circ}\text{C}$	50	-	-	V
$V_{\text{GS(th)}}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 9; see Figure 10	1.8	2.3	2.8	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see Figure 11	0.5	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	1.1	1.5	2	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see <u>Figure 10</u>	-	-	3.3	V
		$I_D$ = 2.5 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 175 °C; see Figure 10	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	500	μΑ
		$V_{DS}$ = 55 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μΑ
$I_{GSS}$	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ see Figure 13	-	11.1	13	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ see Figure 13	-	11.4	12	mΩ
		$V_{GS} = 10 \text{ V; } I_D = 25 \text{ A; } T_j = 25 \text{ °C;}$ see <u>Figure 14</u>	-	4.2	4.9	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 14</u>	-	5.2	6.6	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 14	-	5.7	7.7	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 15 A; $T_j$ = 25 °C; see <u>Figure 13</u>	-	10	11.7	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 15; see Figure 14	-	-	10.8	mΩ
Dynamic o	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D$ = 45 A; $V_{DS}$ = 15 V; $V_{GS}$ = 4.5 V; $T_j$ = 25 °C; see <u>Figure 16</u> ; see <u>Figure 17</u>	-	5.9	-	С
		$I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $V_{GS} = 5 \text{ V}$ ; see <u>Figure 18</u> ; see <u>Figure 17</u>	-	67	-	nC
		$I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $V_{GS} = 10 \text{ V}$ ; see Figure 17; see Figure 18	-	124	-	nC

 Table 6.
 Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$Q_{GS}$	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	19	-	nC
$Q_{GD}$	gate-drain charge	see Figure 18; see Figure 17	-	31.5	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	5800	7750	pF
Coss	output capacitance	$T_j = 25 \text{ °C}$ ; see Figure 19	-	550	660	pF
C <sub>rss</sub>	reverse transfer capacitance		-	380	520	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 45 \text{ V}; R_L = 1.8 \Omega; V_{GS} = 10 \text{ V};$	-	25	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega$	-	65	-	ns
$t_{d(off)}$	turn-off delay time		-	252	-	ns
t <sub>f</sub>	fall time		-	116	-	ns
L <sub>D</sub>	internal drain inductance	from source lead to source bond pad; $T_j = 25$ °C	-	7.5	-	nΗ
L <sub>S</sub>	internal source inductance	from upper edge of drain mounting base to centre of die; $T_j = 25 ^{\circ}\text{C}$	-	3.5	-	nΗ
Source-drai	n diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 20	-	0.83	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	55	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}$	-	112	-	nC

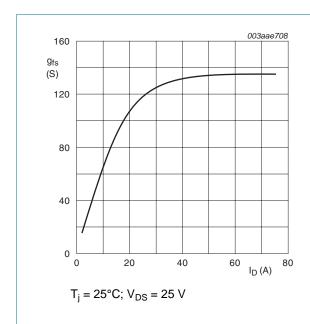


Fig 5. Forward transconductance as a function of drain current; typical values

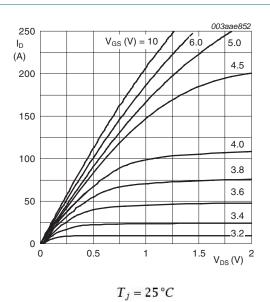


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

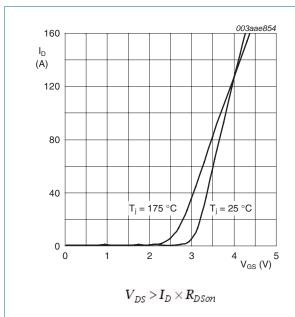
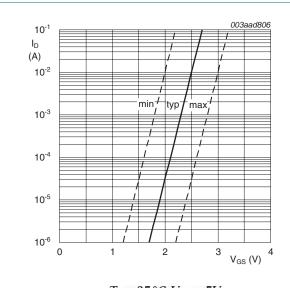
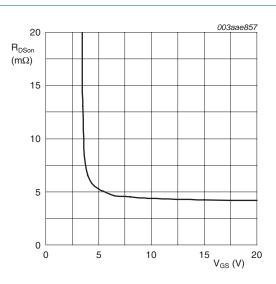


Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_j = 25\,^{\circ}C; V_{DS} = 5V$ 

Fig 9. Sub-threshold drain current as a function of gate-source voltage



 $T_j = 25 \,^{\circ}C; I_D = 25A$ 

Fig 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

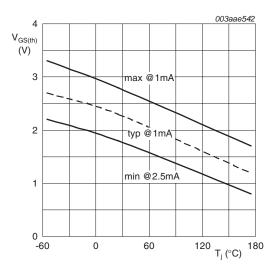


Fig 10. Gate-source threshold voltage as a function of junction temperature

 $I_D = 1mA; V_{DS} = V_{GS}$ 

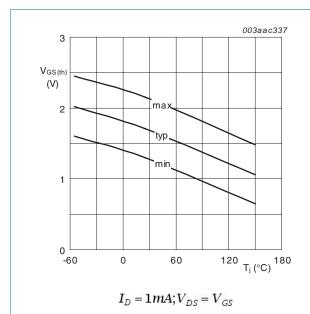


Fig 11. Gate-source threshold voltage as a function of junction temperature

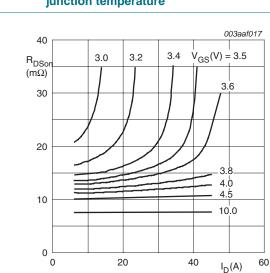
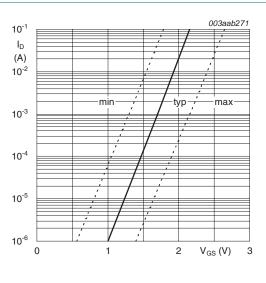


Fig 13. Drain-source on-state resistance as a function of drain current; typical values

 $T_j = 25$ °C



 $T_j = 25 \,^{\circ}C; V_{DS} = 5 \, V$ 

Fig 12. Sub-threshold drain current as a function of gate-source voltage

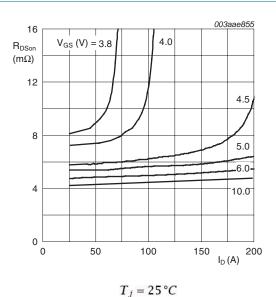


Fig 14. Drain-source on-state resistance as a function of drain current; typical values

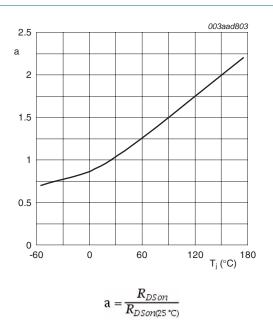


Fig 15. Normalized drain-source on-state resistance factor as a function of junction temperature

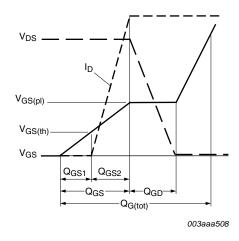


Fig 17. Gate charge waveform definitions

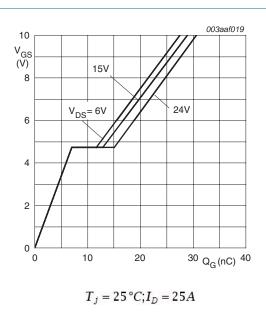
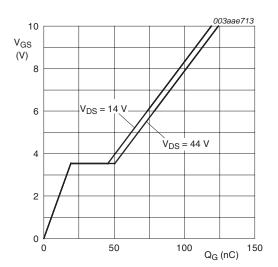


Fig 16. Gate-source voltage as a function of gate charge; typical values



 $T_i = 25^{\circ}C; I_D = 25 A$ 

Fig 18. Gate-source voltage as a function of gate charge; typical values

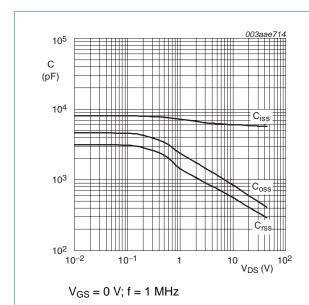


Fig 19. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

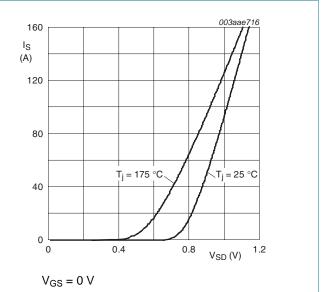


Fig 20. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

## 7. Package outline

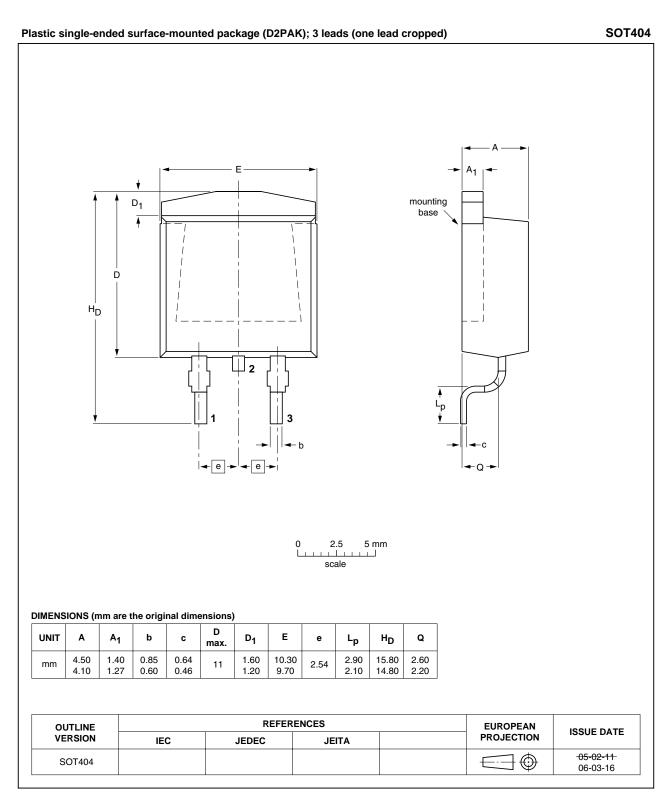


Fig 21. Package outline SOT404 (D2PAK)

# 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK664R4-55C v.3	20101221	Product data sheet	-	BUK664R4-55C v.2
Modifications:	<ul> <li>Status change</li> </ul>	d from objective to product.		
	<ul> <li>Various chang</li> </ul>	es to content.		
BUK664R4-55C v.2	20100923	Objective data sheet	-	BUK664R4-55C v.1

## 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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#### N-channel TrenchMOS intermediate level FET

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